



CMOS MEMS: a Platform Technology for Microsystems

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Outline

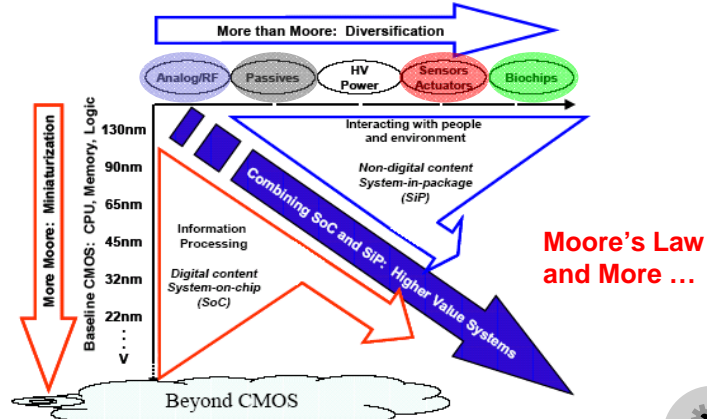
- **Introduction**
- CMOS MEMS Fabrication Platform
- Application: CMOS MEMS Sensors
- Extension of CMOS MEMS Technology
- CMOS MEMS in Taiwan
- Outlook and Concluding Remarks





Moore's Law and More

- Small and Smart
- Add value to the existing CMOS tech

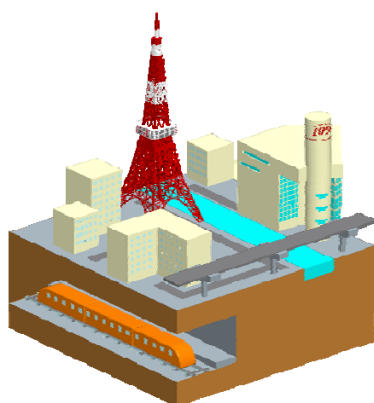


Source: ITRS Roadmap 2005, www.itrs.net

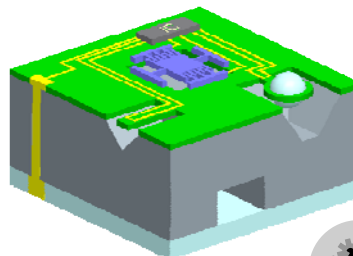


MEMS vs IC

- From *Planar Technology* to *3D Architecture on Chip*



m ~ km



μm ~ mm



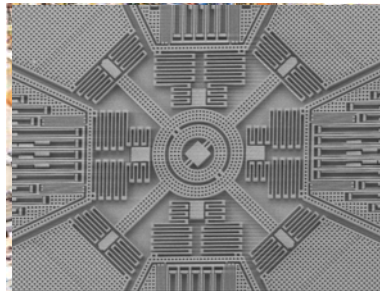


MEMS vs ME

- From *Parts Assembly* to *Process Integration*



www.precisionsmd.com



SensorDynamics.com



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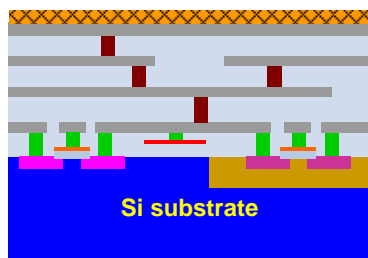




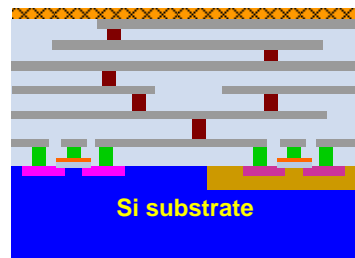
CMOS Fabrication Platform

- Mature CMOS processes: 2P4M, 1P6M, etc...
- Available CMOS foundries: TSMC, UMC, etc...

0.35 μ m 2P4M CMOS process

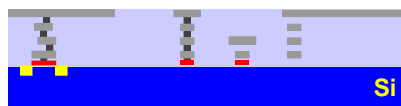


0.18 μ m 1P6M CMOS process



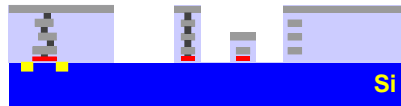
IC vs MEMS

CMOS process

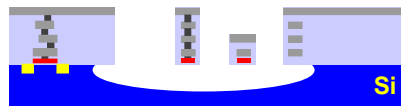


IC

Thin film etching



Bulk Si etching



IC + MEMS

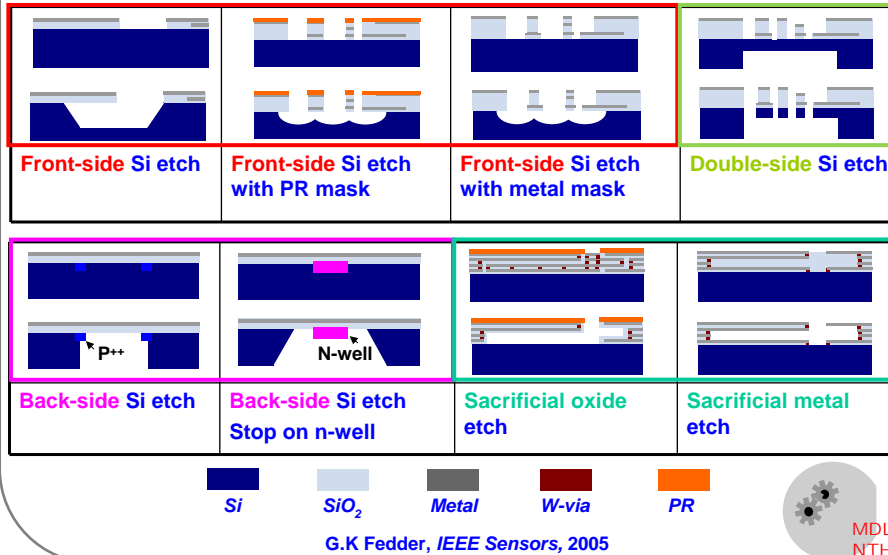
Oxide Metal Poly W

TSMC 2P4M process

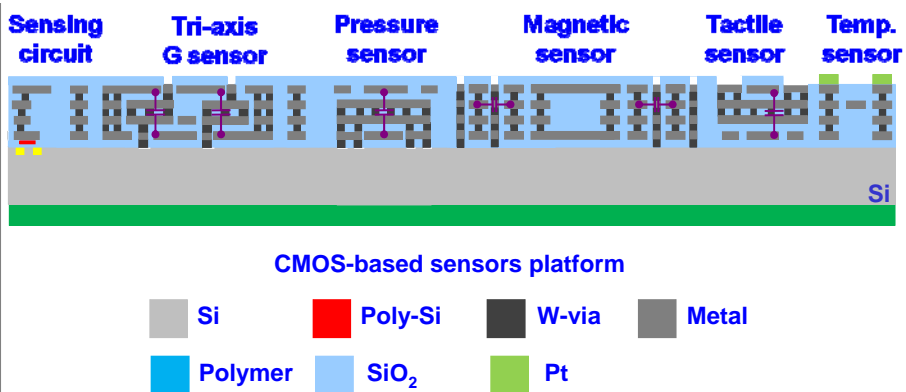




CMOS post process – for MEMS



CMOS-MEMS Sensors Platform

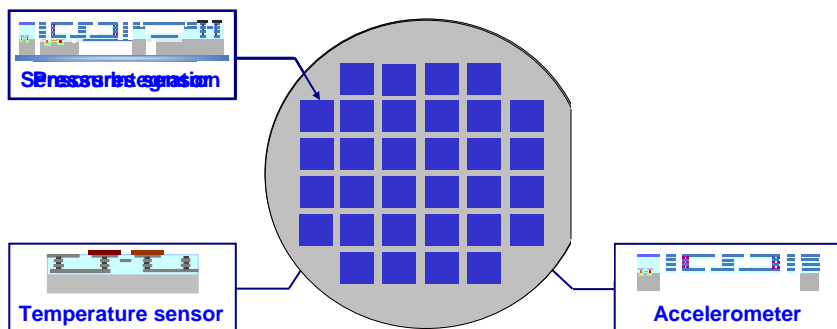


- Standard TSMC 0.35mm 2P4M CMOS process
- Post-CMOS processes developed by Prof. Fang's group





- **Batch of Sensor, Multi Sensors, and Sensors Integration**



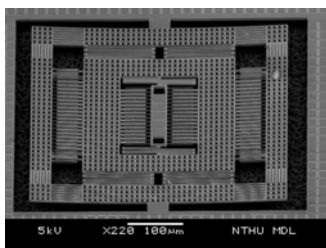
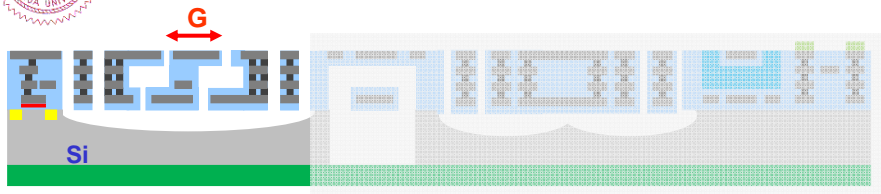
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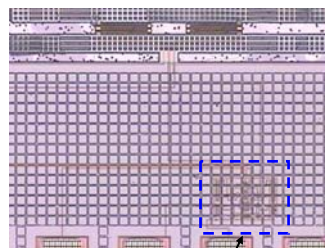




1-axis G-sensor



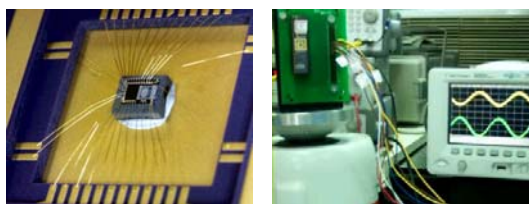
MEMS structure



CMOS IC



1-axis G-sensor



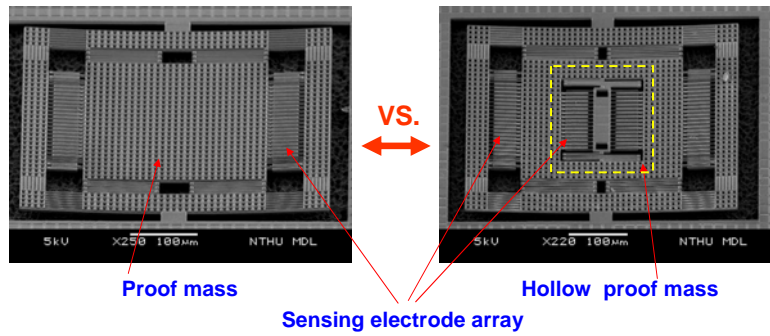
	Hollow proof-mass
Measurement Range (G)	0.3~10
Sensitivity (mV/G)	3.95
Resonant Freq. (kHz)	5.83
Nonlinearity (%)	2.75
Cross-axis sensitivity_Y (%)	1.05
Cross-axis sensitivity_Z (%)	< 1

Sun, and Fang, *IEEE Sensors*, 2006
Sun, and Fang, *Sens. Actuators A*, 2008

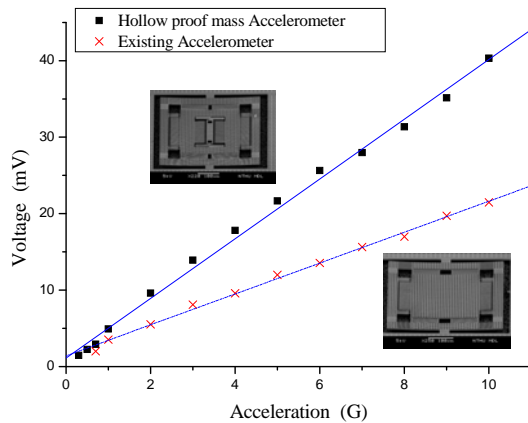




- **Hollow proof mass Accel. – sensitivity improvement**



Sun, Wang, Tsai, and Fang, *Sensors and Actuators A*, 2008

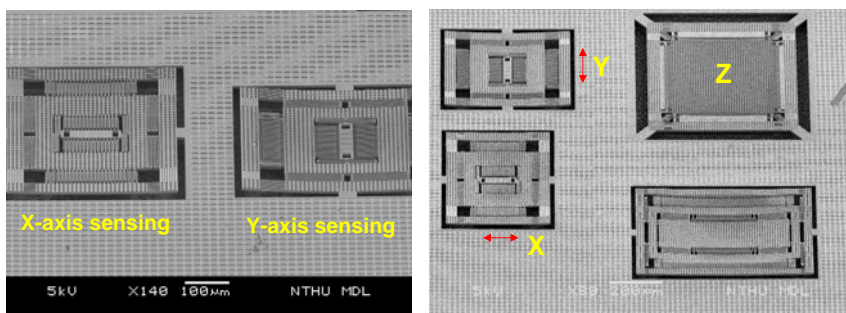


Sensitivity improved from 2.1mV/G to 3.95mV/G





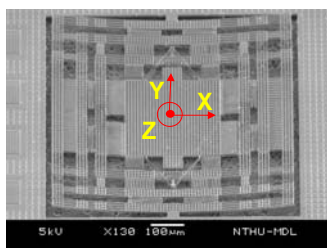
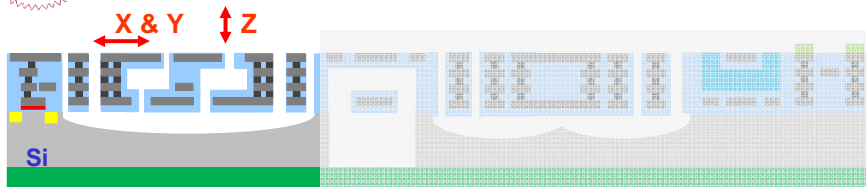
- **Multi-axes Accel. by integrating of multi 1-axis Accel.**



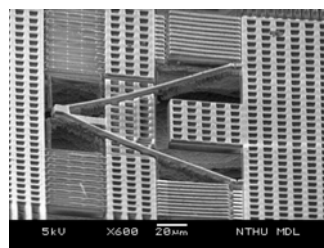
Tsai, Wang, Sun, and Fang, *IEEE NEMS'08 (best paper finalist)*, SanYa, China, 2008



3-axis G-sensor

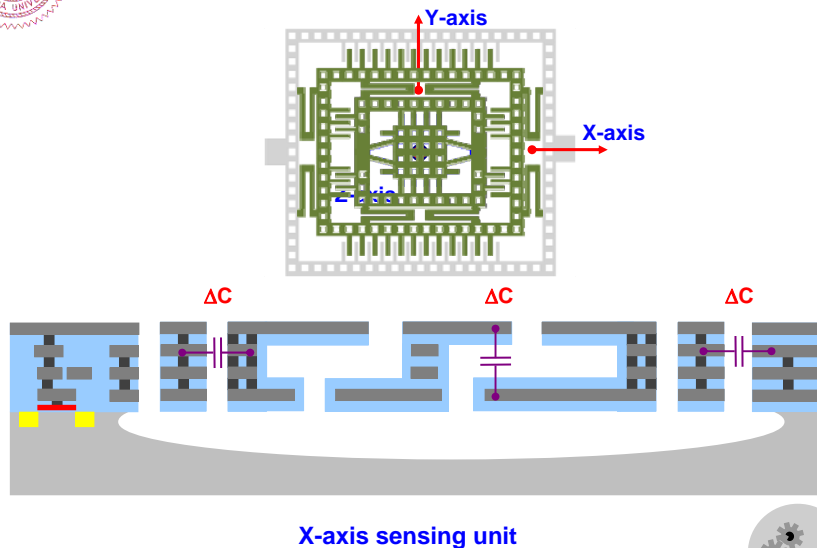


Single proof-mass

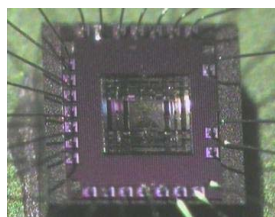


Z-spring





3-axis G-sensor



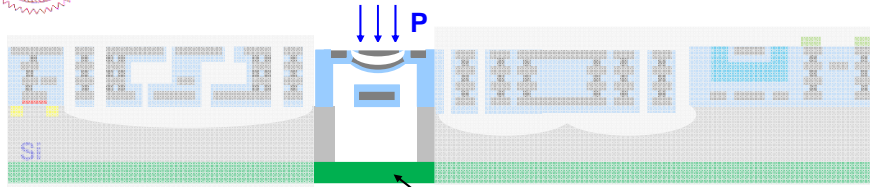
	<i>X-axis</i>	<i>Y-axis</i>	<i>Z-axis</i>
Sensitivity (mV/G)	0.53	0.28	0.20
Non-linearity (%)	2.64	3.15	3.36
Noise floor (mG/rtHz)	120	271	357
Cross-axis sensitivity _X(%)		< 7.46	< 2.88
Cross-axis sensitivity _Y(%)	< 1		< 8.05
Cross-axis sensitivity _Z (%)	< 1	< 8.33	

Sun, and Fang, *IEEE MEMS*, 2009
 Sun, and Fang, *IEEE Trans. on ED*, 2010



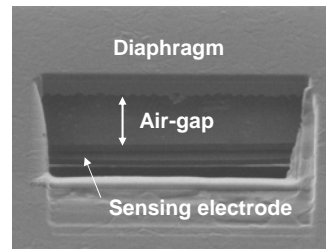
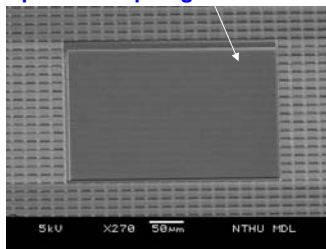


Pressure Sensors



Suspended diaphragm

Packaging

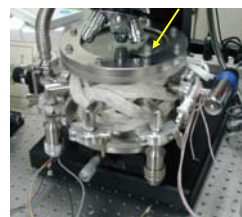
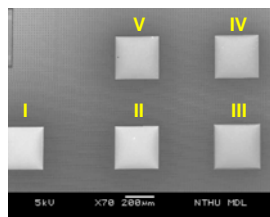







FIB sectioning

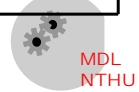


Pressure Sensors

Pressure load chamber

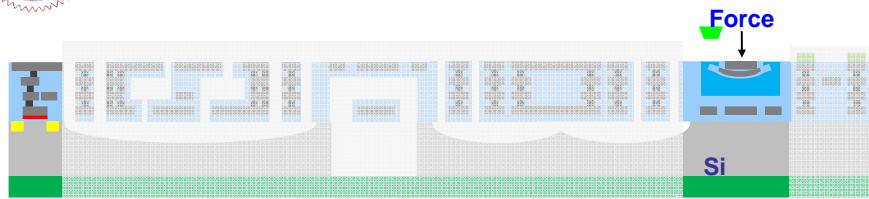


					
Diaphragm Thickness	1.925 μm	3.56 μm	3.56 μm	1.64 μm	1.925 μm
Sensitivity	0.04 fF/KPa	0.02 fF/KPa	0.042 fF/KPa	0.36 fF/KPa	0.23 fF/KPa
Sensing Range	0~500 KPa	90~500 KPa	100~500 KPa	0~60 KPa	0 ~ 90 KPa

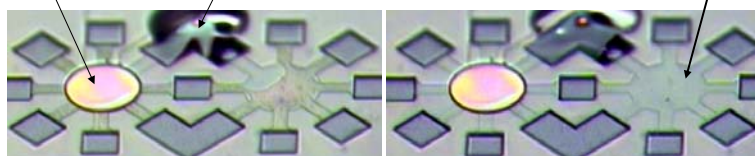




Tactile Sensor w Polymer Fill-in



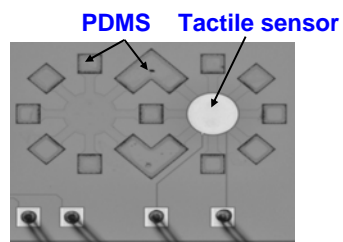
Tactile sensor Polymer inlet hole Monitor testkey



Polymer fill-in to modulate sensitivity and sensing range



Tactile Sensor w Polymer Fill-in



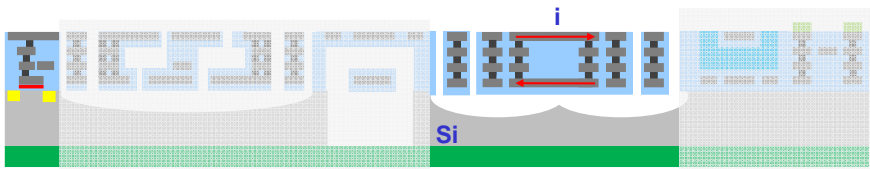
Gap material	Air	PDMS (1:1)	PDMS (1:5)	PDMS (1:10)
Initial capacitance, C_0 (fF)	99	299	287	284
Sensitivity (mV/mN)	31.29	63.36	39.03	18.38
Sensing range (mN)	0.1~0.5	0.3~0.7	0.3~1.0	0.5~1.8
Non-linearity (%)	1.6	5.6	3.5	3.5

Liu, and Fang, *IEEE Transducers'09*, 2009
Liu, and Fang, *IEEE JMEMS*, 2011





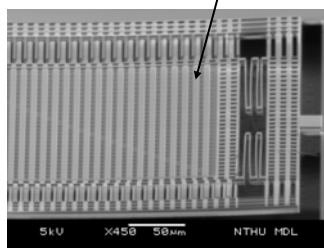
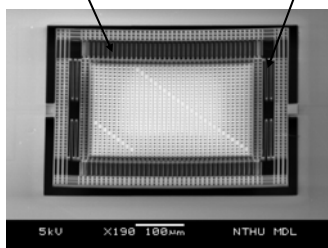
Magnetic Sensors



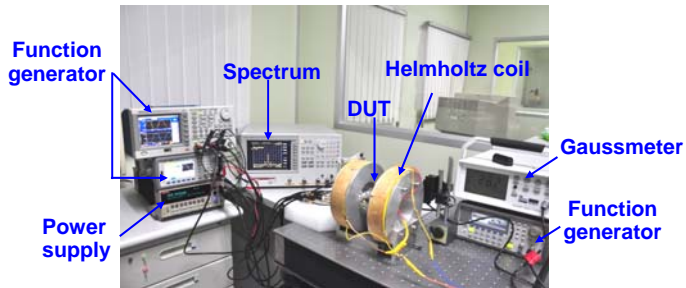
Fingers

Spring

Coil



Magnetic Sensors



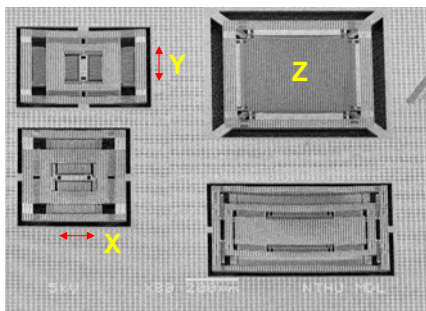
Magnetic Field	X	Y	Z
Current (mA)	4.18	4.02	4.02
Sensitivity (mV/mT)	0.13	0.14	1.51
Resolution (nT/rtHz)	319.9	296.5	121.6
Nonlinearity (%)	2.27	3.27	2.24
Pressure	1atm		

Chang, and Fang, *IEEE MEMS*, 2013

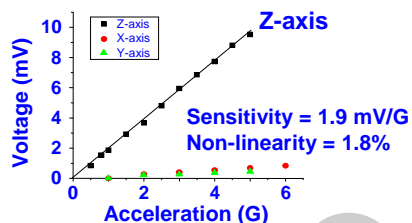
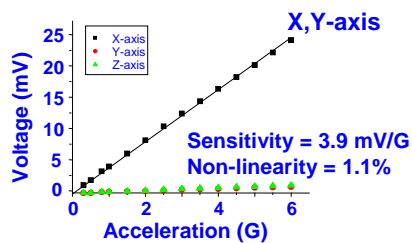




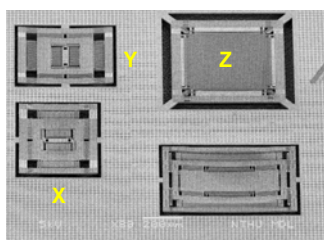
Sensor Integration: G/G/G Sensors



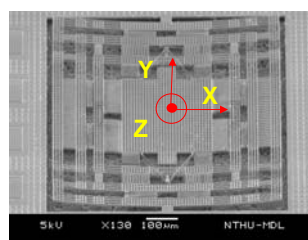
0.35 μ m CMOS process integration



- Note: ~50% chip footprint reduction by single unit



Three 1-axis units



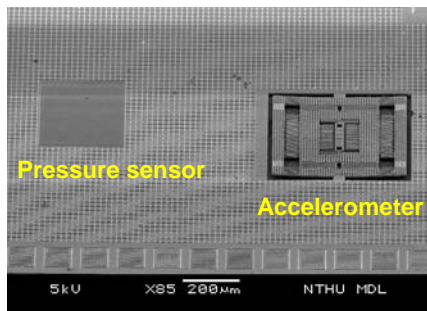
One 3-axis unit

Sun, Tsai, and Fang, *IEEE MEMS*, 2009
Sun, Tsai, and Fang, *IEEE Trans on ED*, 2010

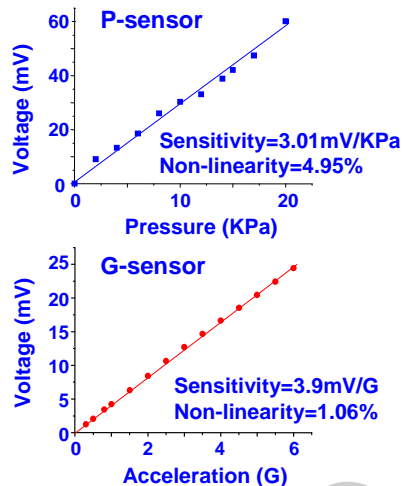




Sensor Integration: G/P Sensors



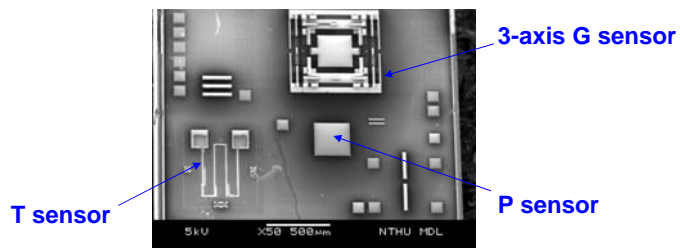
0.35 μ m CMOS process integration



Sun, and Fang, *IEEE MEMS*, 2008
Sun, and Fang, *IEEE Transducers*, 2009



Sensor Integration: G/P/T Sensors



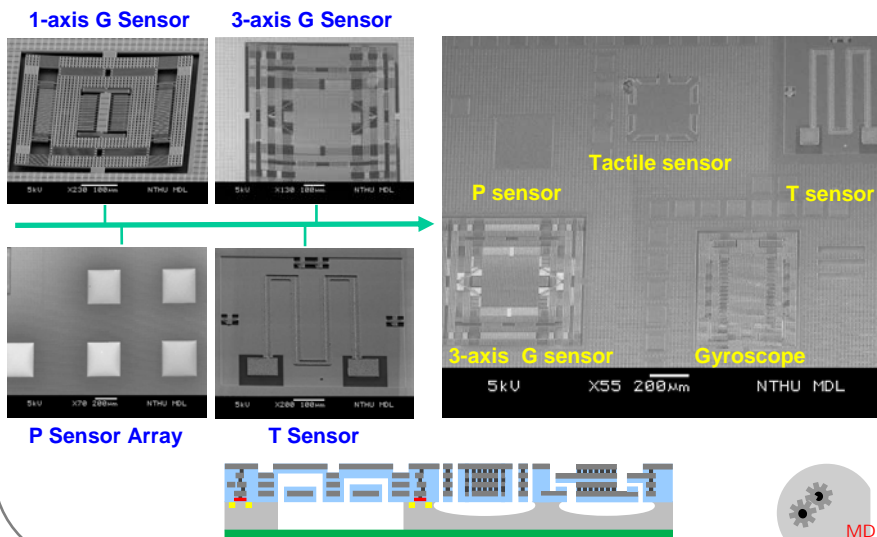
Monolithic sensors integration			
Sensor	3-axis G-sensor	P-sensor	T-sensor
Sensitivity	0.54 / 0.32 / 0.19 X/Y/Z (mV/G)	2.7 mV/KPa	1.74 mV/°C
Non-linearity	< 5%	4.58 %	4.29 %
Sensing range	0.8~5 G	0~20 KPa	25~150 °C

Sun, and Fang, *IEEE Transducers*, 2009
Sun and Fang, *JMM*, 2009





CMOS-MEMS Sensors Integration



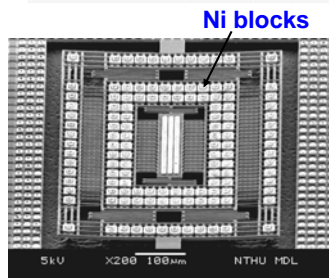
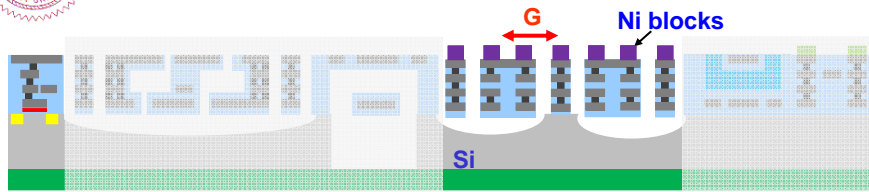
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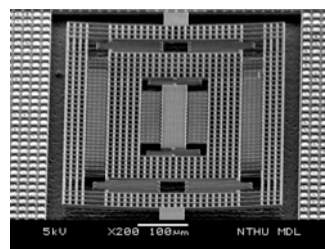




G-sensor w Electroplating-Ni



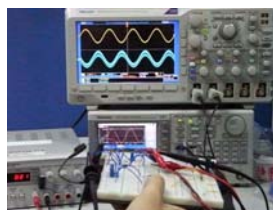
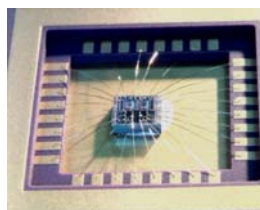
With electroplating



Without electroplating



G-sensor w Electroplating-Ni



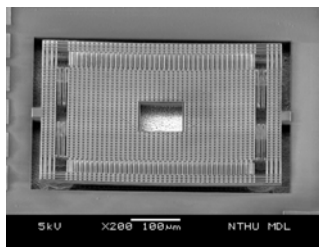
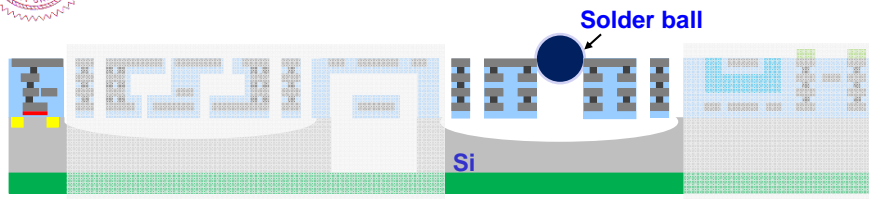
	Without Ni	With Ni
Frequency (kHz)	6.97	4.71
Sensitivity (mV/G)	1.08	2.68
Nonlinearity (%)	2.64	2.81
Noise floor (mG/rt Hz)	8.15	3.28
Resolution (G)	1	0.2

Liu, and Fang, *IEEE Transducers*, 2011
Liu, and Fang, *JMM*, 2011

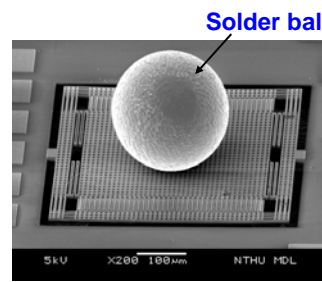




Tilt Sensor w Pick-place Mass



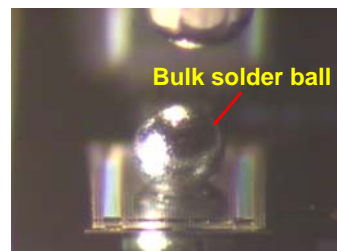
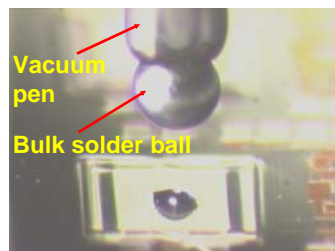
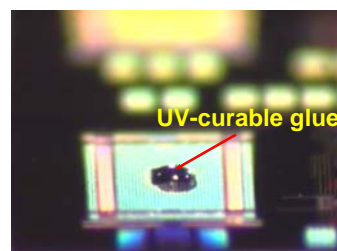
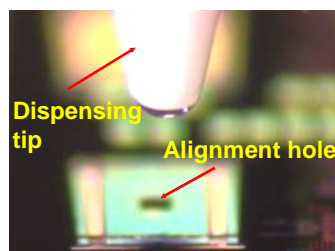
W/O solder ball



W solder ball

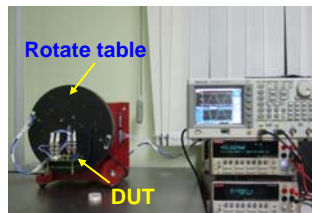
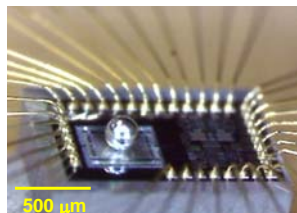


Tilt Sensor w Pick-place Mass





Tilt Sensor w Pick-place Mass

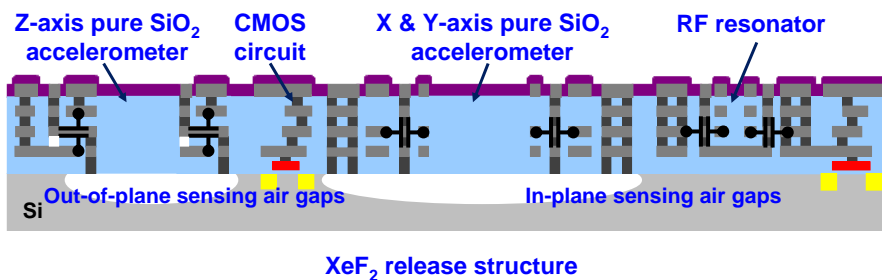


Specifications	W/O bulk ball	With bulk ball
Proof mass (ng)	1.72	62.14
Linear range (°)	0 ~ 45	0 ~ 45
Sensitivity (mV/°)	0.41	1.41
Resolution (°)	1	0.1
Non-linearity (%)	7.6	2.3

Chang, and Fang, *IEEE Transducers*, 2011



Pure oxide-based CMOS-MEMS platform



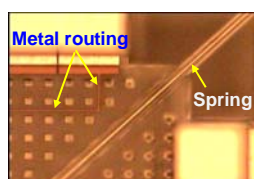
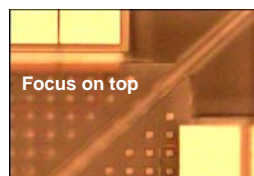
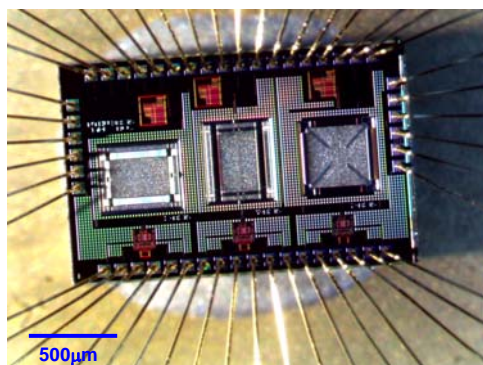
■ Poly
 ■ SiO₂
 ■ Via
 ■ Al
 ■ Passivation





3-axis pure oxide G-sensor

- **G-sensor: Transparent Oxide proof-mass with embedded wires**

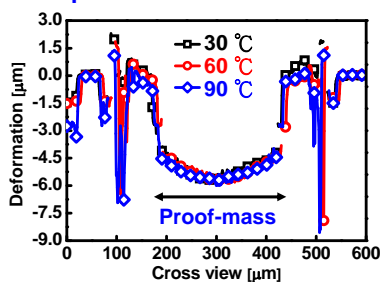


Liu, and Fang, *IEEE MEMS*, 2012

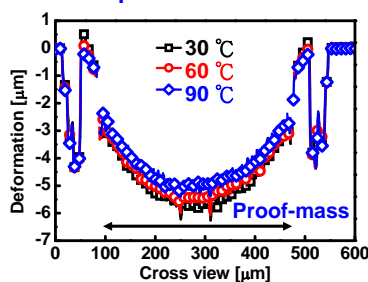


3-axis pure oxide G-sensor

◆ In-plane



◆ Out-of-plane

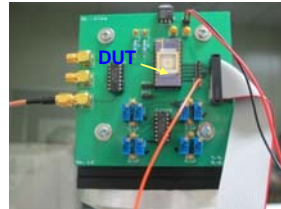
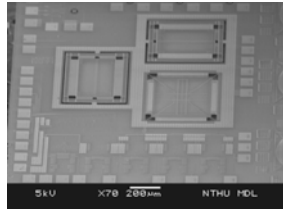


	X-axis	Y-axis	Z-axis
Temperature [°C]	ROC [mm]	ROC [mm]	ROC [mm]
30	9.43	9.55	6.07
60	9.82	9.76	6.51
90	10.35	10.31	6.96
ROC change with temperature (%/°C)	0.16	0.13	0.24





Pure oxide CMOS device

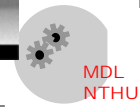
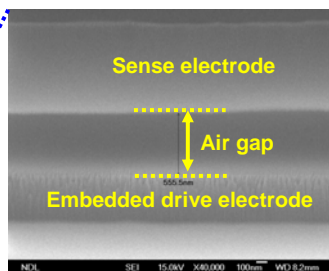
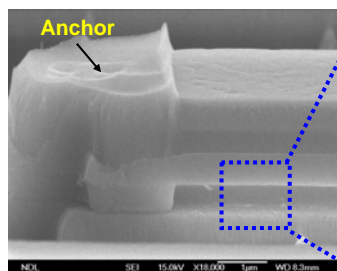
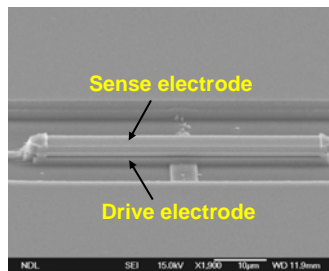
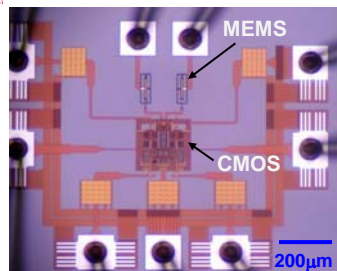


Sensing-axis	X-axis	Y-axis	Z-axis
Measurement Range (G)	±2		
Sensitivity (mV/G)	105.2	127.4	57.7
Non-linearity (%)	1.01	0.52	2.43
Noise (mG/sqrtHz)	0.4	0.21	0.94
Cross-axis sensitivity _X(%)		1.57	6.41
Cross-axis sensitivity _Y(%)	1.05		6.07
Cross-axis sensitivity _Z (%)	2.86	1.65	

Liu, and Fang, *IEEE MEMS*, 2012

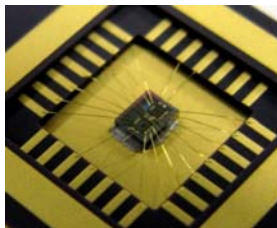


Pure oxide resonator





Pure oxide resonator

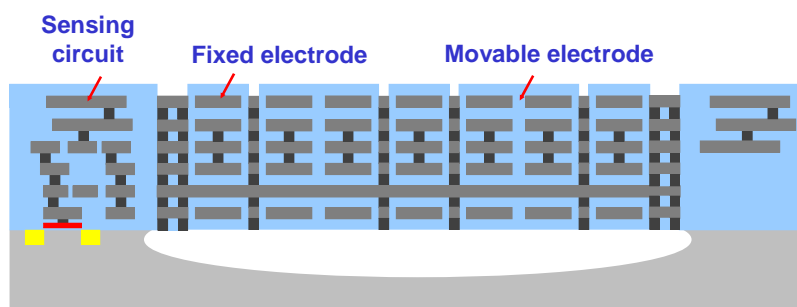


Mode Type	Out-of-plane CC-beam
Temp. Frequency Change	30,000ppm (-40~80°C)
Frequency, f_o	3.01MHz
DC-Bias Voltage, V_p	170V
Quality Factor, Q	4,400
$f_o \times Q$ Product	1.37×10^{10}
Stopband Rejection, SB_{rej}	80dB
Insertion Loss, IL	11.81dB

Liu, and Fang, *IEEE Transducers*, 2011



0.18 μm 1P6M Process

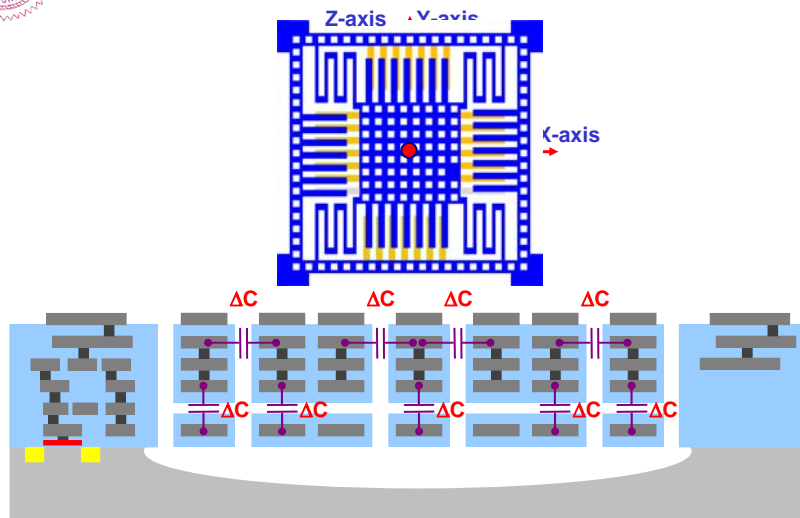


XeF₂ release structure



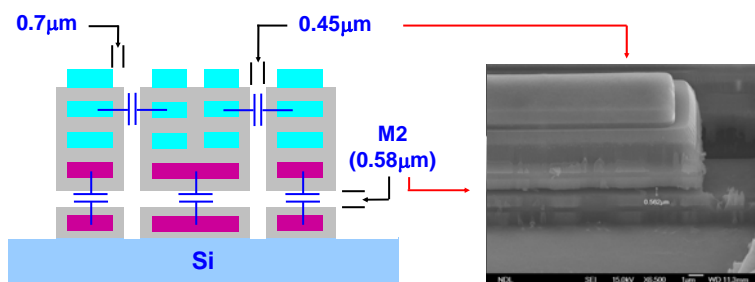


3-axis G-sensor



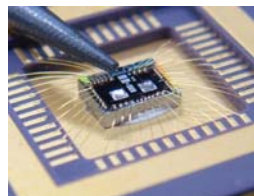
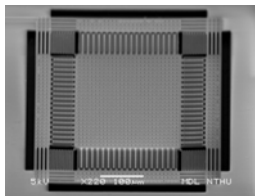
3-axis G-sensor

- Sub-micron sensing gap by 0.18um process





3-axis G-sensor



Single proof-mass 3-axis G-sensor .18μm CMOS process (0.4mm×0.4mm)

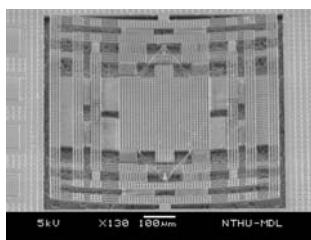
Sensing-axis	X-axis	Y-axis	Z-axis
Measurement Range (G)	0.01~1	0.01~1	0.01~1
Sensitivity (mV/G)	14.2	14.6	8.0
Non-linearity (%)	3.0	1.5	1.8
Noise (mG/sqrtHz)	1.9	2.9	3.4
Cross-axis sensitivity _X(%)		8.1	2.3
Cross-axis sensitivity _Y(%)	7.4		8.0
Cross-axis sensitivity _Z (%)	5.7	6.4	

Tsai, and Fang, *IEEE Transducers*, 2011

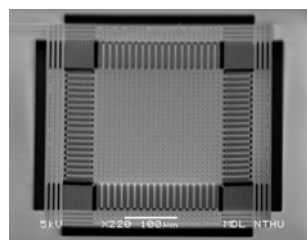


3-axis G-sensor

- Note: ~3-fold footprint reduction by 0.18μm process



0.35μm process
 Footprint: 0.7mm ×0.7mm
 Sensitivity (mV/G): 0.5, 0.3, 0.2



0.18μm process
 Footprint: 0.4mm ×0.4mm
 Sensitivity (mV/G): 14.2, 14.6, 8.0

Tsai, and Fang, *IEEE JMEMS*, 2012



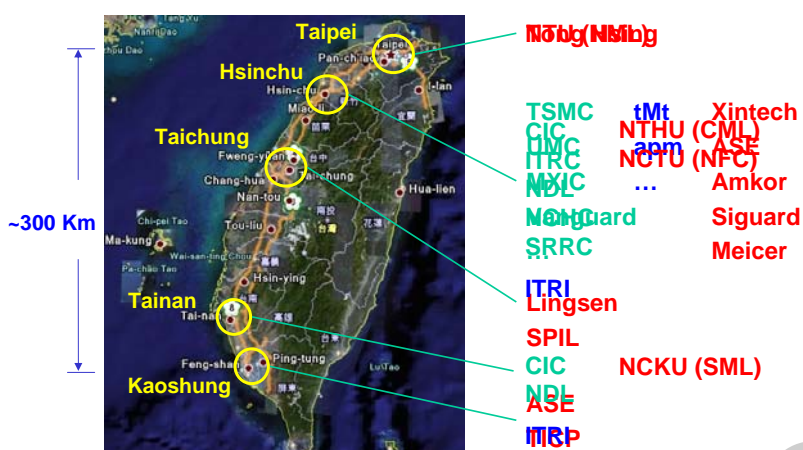


Outline

- Introduction
- CMOS MEMS Fabrication Platform
- Applications: CMOS MEMS Sensors
- Extension of CMOS MEMS Technology
- **CMOS MEMS in Taiwan**
- Outlook and Concluding Remarks



CMOS MEMS Eco-system at Taiwan

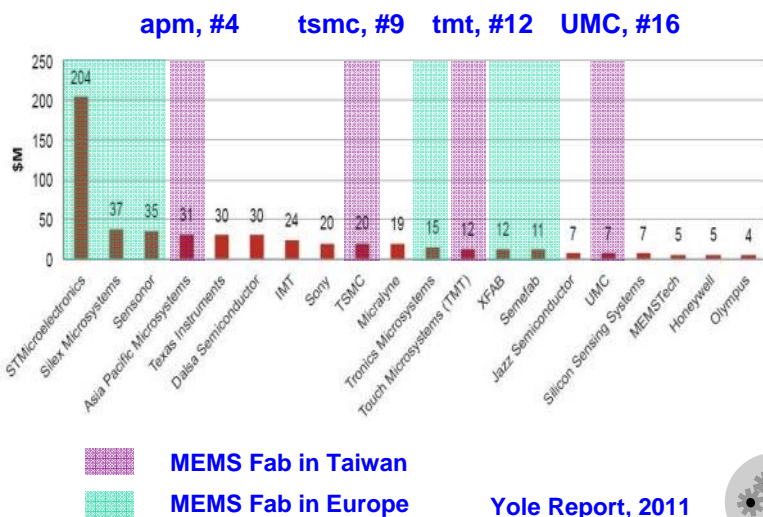


National OS Fab Res MEMS Inst. Packag MEMS Fabr





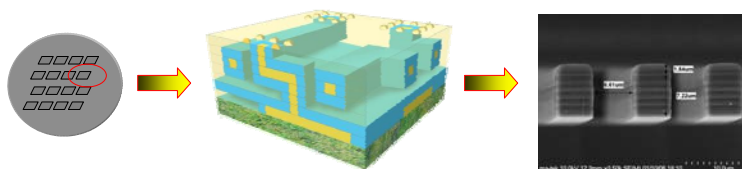
World Top-20 MEMS Foundry



CIC Service for Academia



- **CIC: Chip Implementation Center, founded by Gov.**
- **TSMC CMOS Process (for MEMS)**
+ 0.35 μ m 2-Poly 4-Metal CMOS process (from 2002, 5 runs/year)
+ 0.18 μ m 1-Poly 6-Metal CMOS process (from 2006, 3 runs/year)
- **APM Post-CMOS Process to release MEMS designs**

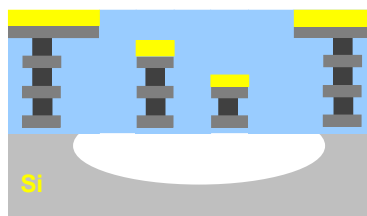


Source : CIC





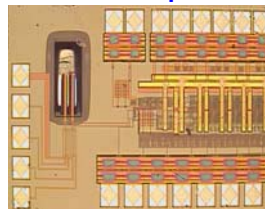
CMOS Bio-MEMS



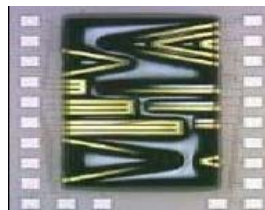
XeF₂ releasing

■ W-via ■ Metal ■ SiO₂ ■ Au

- CMOS Bio chip



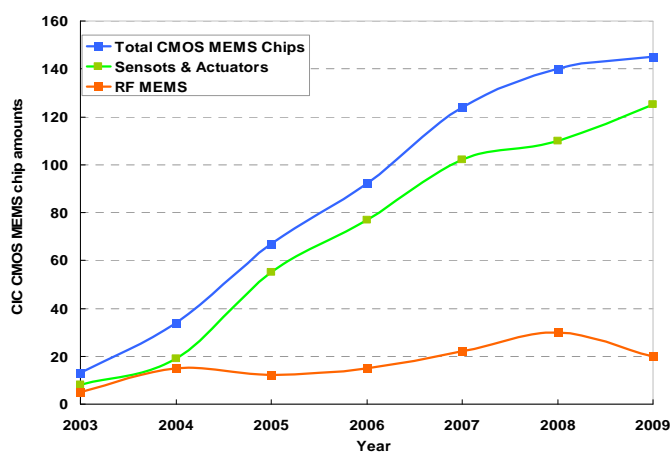
- Au cantilever beam



Source : CIC



CMOS MEMS Design via CIC

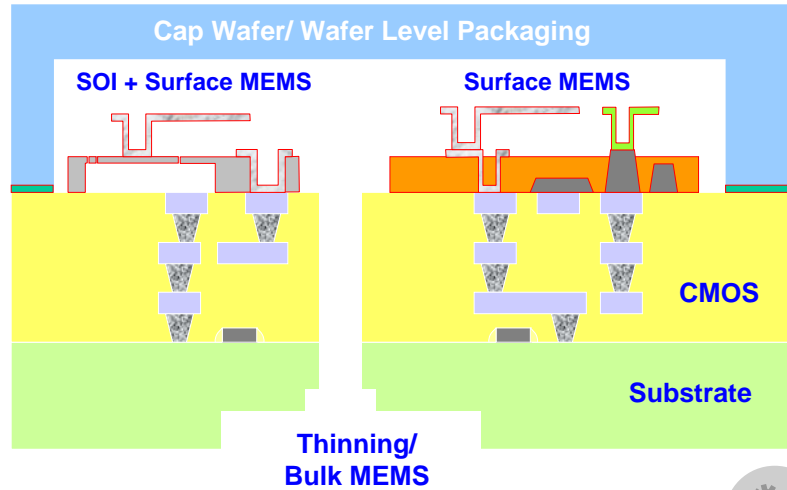


Source : CIC





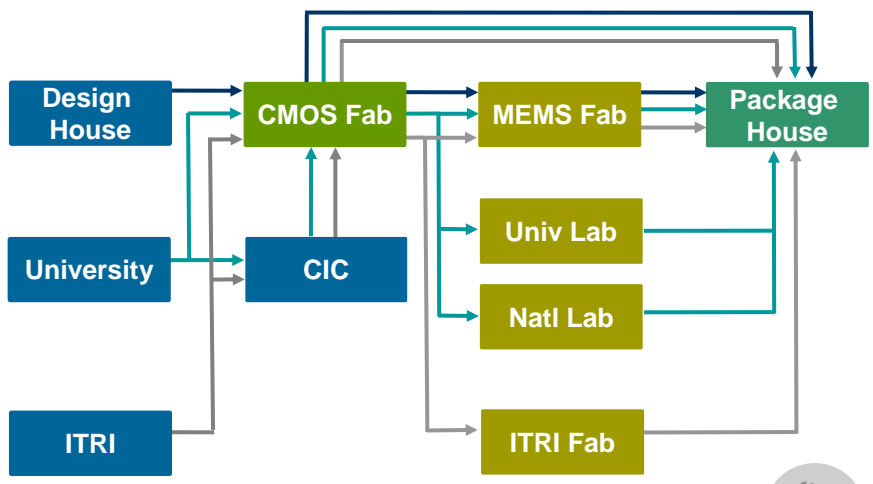
TSMC MEMS Process Capability



Source : TSMC, 2008

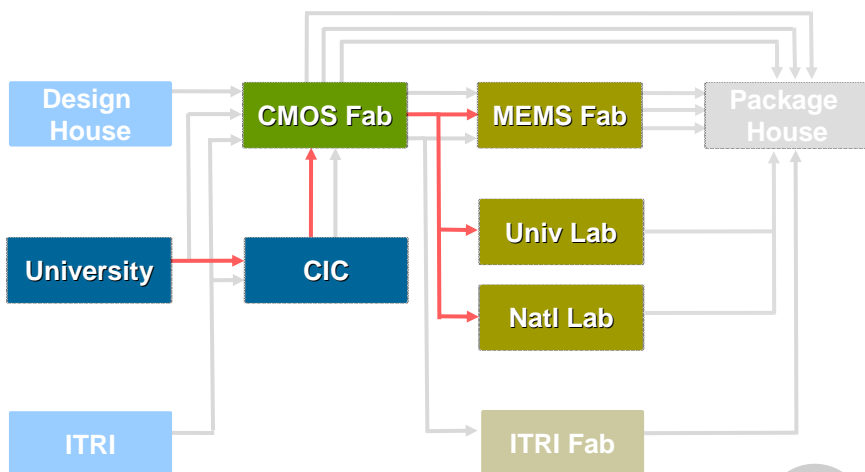


CMOS MEMS Networks at Taiwan





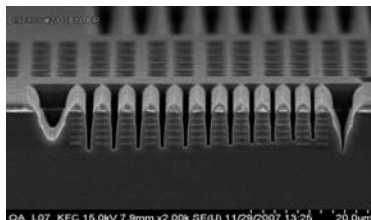
CMOS MEMS Networks at Taiwan



CMOS Films Mech. Properties - TSMC



Test cantilever for TSMC Process



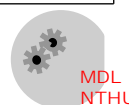
Test key for loading effect

Mechanical properties extraction:

- Density
- Young's Modulus
- Residual stresses
- Residual stress gradient

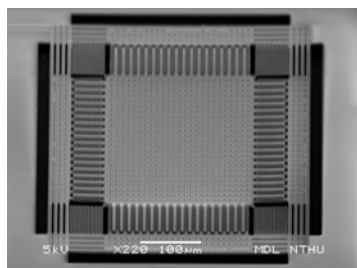
Properties	Value
Al film Density	2600~2800 kg/m ³
SiO ₂ Young's Modulus	55~60 GPa
SiO ₂ Residual stress	240~250 MPa
Poly Residual stress	180~190 MPa
SiO ₂ Stress gradient	40~50 MPa

Preliminary results

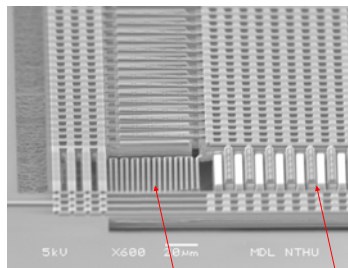




0.18um 1P6M CMOS Process - TSMC



3-axis accelerometer

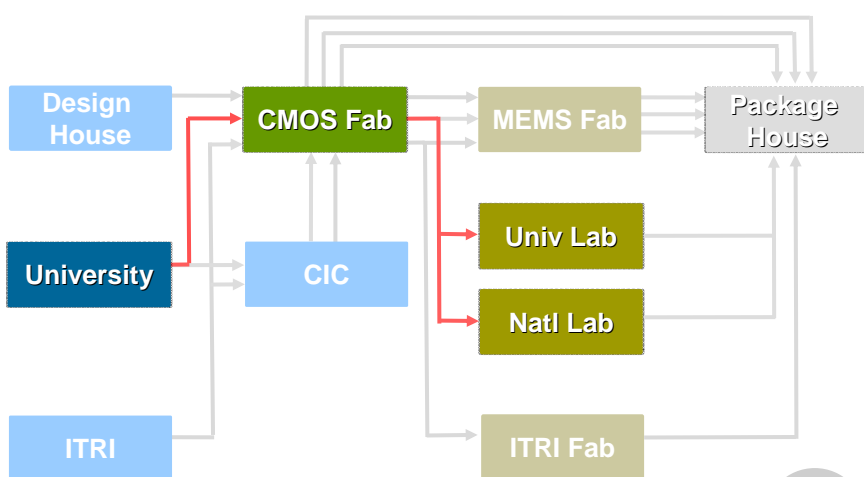


Spring Electrodes

Sensing-axis	X-axis	Y-axis	Z-axis
Measurement Range (G)	0.01~1	0.01~1	0.01~1
Sensitivity (mV/G)	14.2	14.6	8.0
Non-linearity (%)	3.0%	1.5%	1.8%
Noise (mG/sqrtHz)	1.9	2.9	3.4



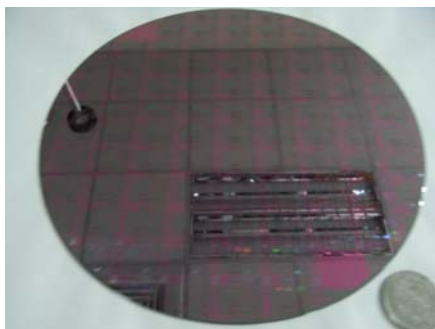
CMOS MEMS Networks at Taiwan



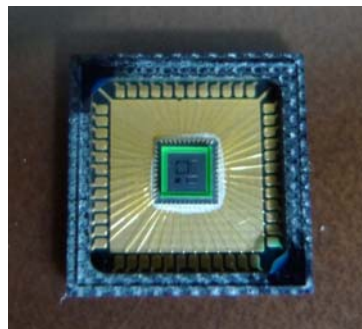


CMOS MEMS Sensors – X Design House

- 8-in 0.18um processes other than TSMC



CMOS MEMS on 8" Wafer

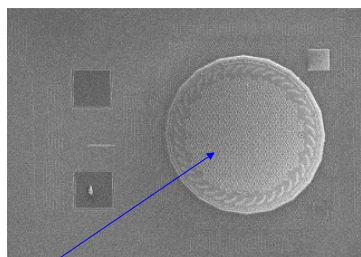


CMOS MEMS Sensors after bonding

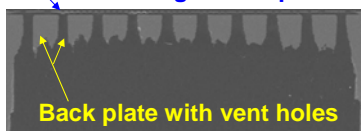


CMOS MEMS Sensors – Y Design House

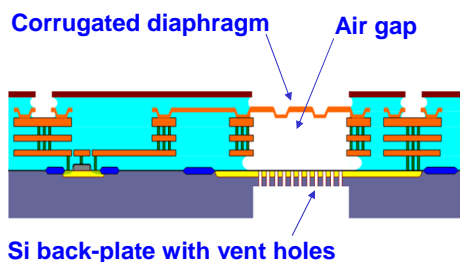
- **Microphone:** 8-in 0.18um UMC CMOS processes



Corrugated diaphragm



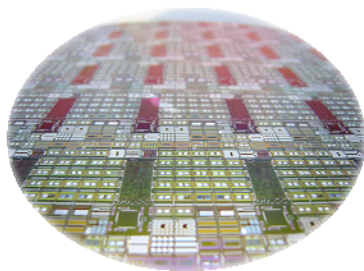
Back plate with vent holes



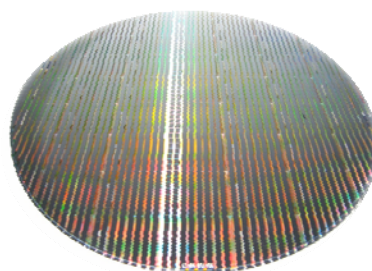


CMOS MEMS Sensors

- 8-in 0.18um UMC processes
- ITE/Univ. - UMC - SPIL - KYEC



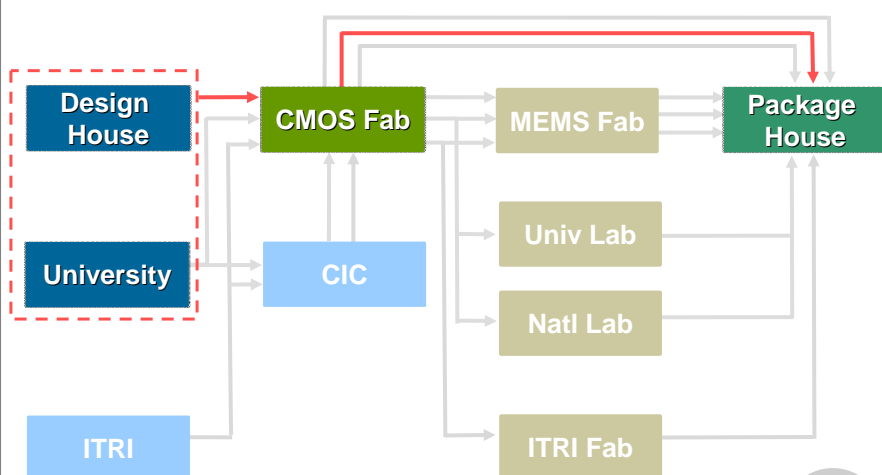
CMOS MEMS on 8" Wafer - UMC



Capped CMOS MEMS Sensors - SPIL



CMOS MEMS Networks at Taiwan



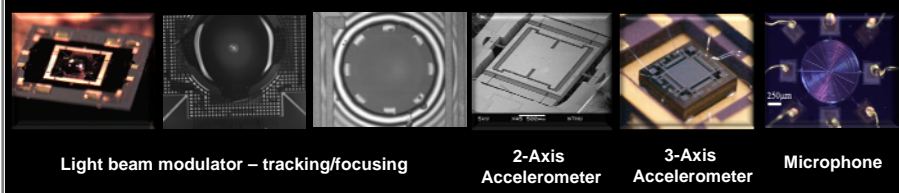
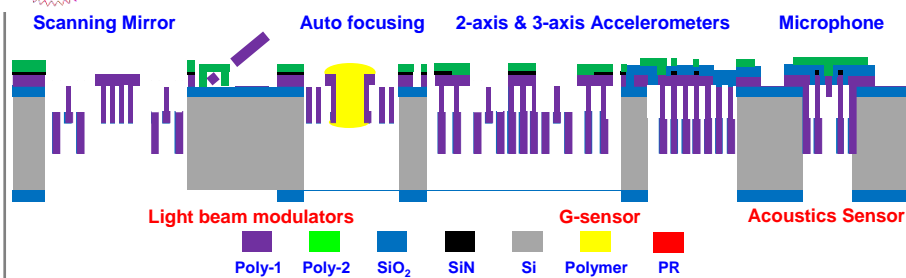


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Poly-Silicon Platform



Wu, and Fang, *J. Micromech. Microeng.*, 2005

Wu, and Fang, *J. Micromech. Microeng.*, 2006

Wu, and Fang, *J. Opt. A.*, 2006

Wu, and Fang, *IEEE Photonics Technol. Lett.*, 2006

Wu, and Fang, *IEEE Photo. Tech. Lett.*, 2007

Chan, and Fang, *Transducers*, Denver, 2009

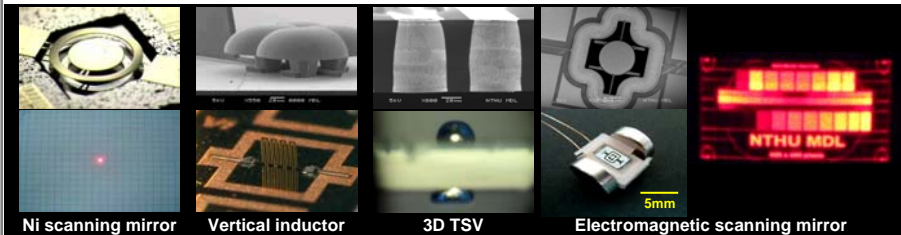
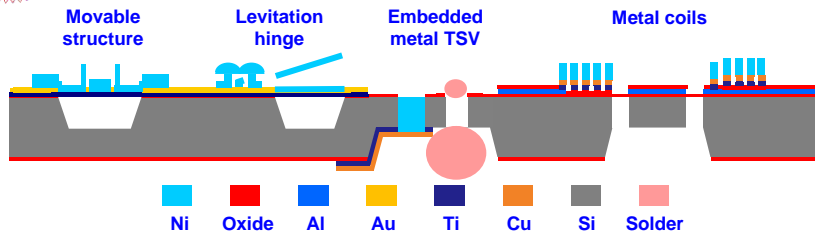
Chan, and Fang, *MEMS*, Hong Kong, 2010

Chan, and Fang, *IEEE Sens. J.*, 2011





Metal-MEMS Platform

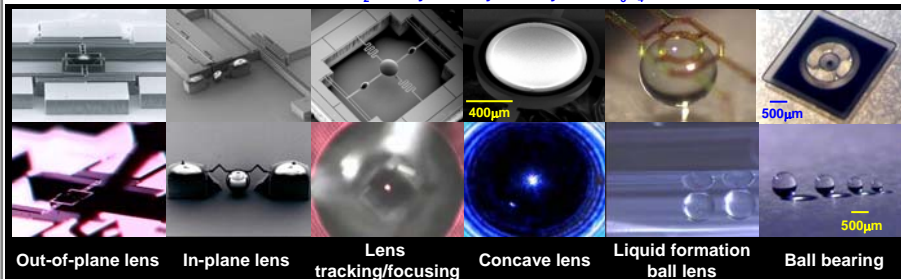
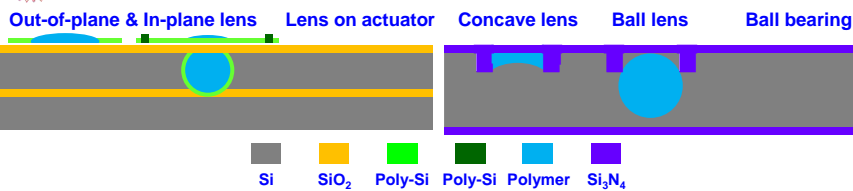


Yang, and Fang, *IEEE MEMS*, Istanbul, 2005
 Yang, and Fang, *JMM*, 2006
 Yang, and Fang, *JMEMS*, 2007
 Su, and Fang, *IEEE MEMS*, Sorrento, 2009

Huang, and W. Fang, *JMMM*, 2010
 Tang, and Fang, *JMM*, 2010
 Tang, and Fang, *IEEE MEMS*, Cancun, 2011
 Tang, and Fang, *JMM*, 2011

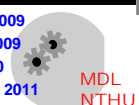


Polymer-MEMS Platform



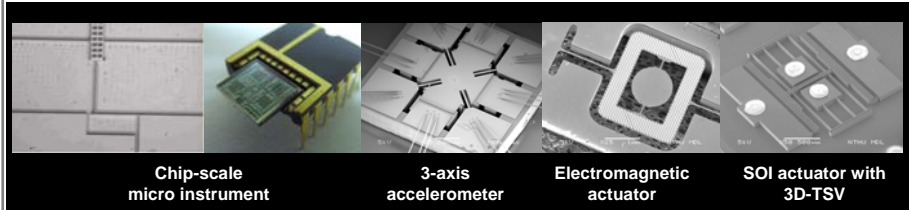
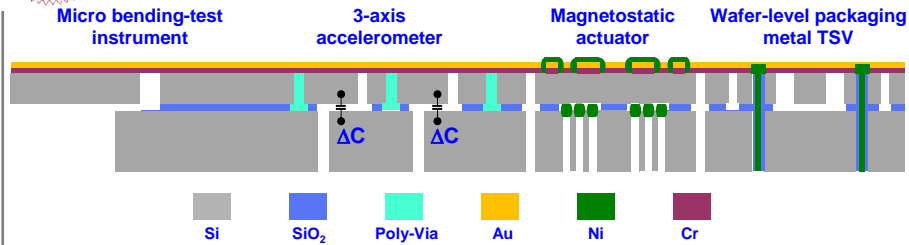
Hsieh, and Fang, *JMM*, 2007
 Tung, and Fang, *IEEE MEMS*, Kobe, Japan, 2007
 Lee, and Fang, *Transducers*, Leon, France, 2007
 Hsiao, and Fang, *IEEE MEMS*, Tucson, USA, 2008

Lee, and Fang, *IEEE MEMS*, Sorrento, Italy, 2009
 Lee, and Fang, *Transducers*, Denver, USA, 2009
 Lee, and Fang, *IEEE MEMS*, Hong Kong, 2010
 Lee, and Fang, *IEEE MEMS*, Cancun, Mexico, 2011





SOI-MEMS Platform

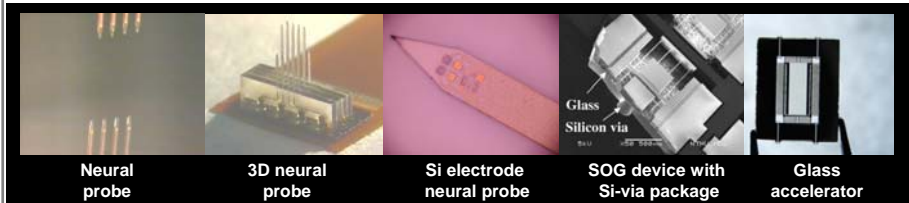
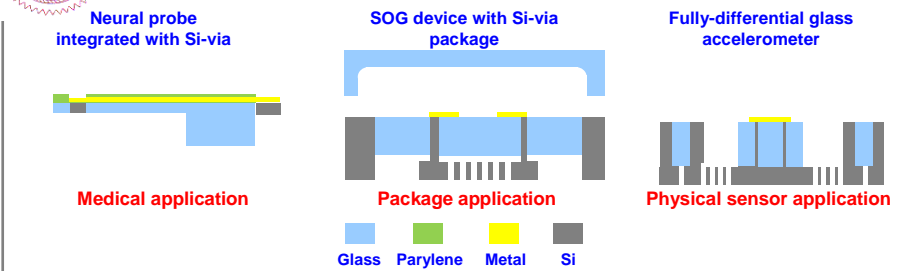


Lin, and Fang, *Transducers*, 2007
 Lin, and Fang, *JMM*, 2007
 Lau, and Fang, *MRS Fall Meeting*, 2007
 Hsu, and Fang, *Transducers*, 2009

Tang, and Fang, *Transducers*, 2009
 Hsu, and Fang, *JMM*, 2009
 Tang, and Fang, *JMM*, 2010
 Hsu, and Fang, *IEEE Sensors*, 2010



Glass-MEMS Platform



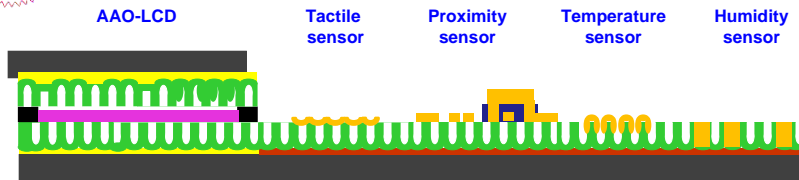
Lin, and Fang, *J. Micromech. Microeng.*, 2008
 Lin, and Fang, *IEEE MEMS*, Sorrento, 2009
 Lin, and Fang, *Biosens. Bioelec.*, 2009
 Lee, and Fang, *Transducers*, Denver, 2009

Lee, and Fang, *Biosens. Bioelec.*, 2009
 Lee, and Fang, *J. Micromech. Microeng.*, 2010
 Hsu, and Fang, *IEEE MEMS*, Hong Kong, 2010
 Lee, and Fang, *IEEE MEMS*, Cancun, 2011



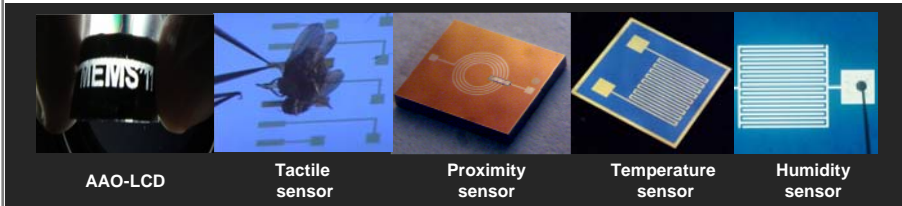


AAO-MEMS Platform



AAO Devices AAO Physical sensor AAO Environment Sensor

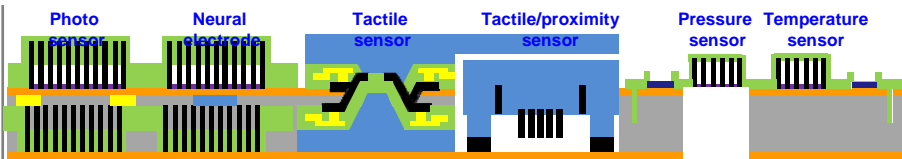
Ti AAO PET Metal ITO SiO₂ Si LC



Hong, and Fang, *IEEE MEMS*, Italy, 2009 Hong, and Fang, *IEEE Sensor J.*, 2011
 Hong, and Fang, *SID*, USA, 2010 Yeh, and Fang, *IEEE SENSORS*, Ireland, 2011
 Hong, and Fang, *Nanotechnology*, 2010 Lo, and Fang, *Transducers*, Beijing, 2011
 Hong, and Fang, *IEEE MEMS*, Mexico, 2011 Hong, and Fang, *Molecular & Liquid Crystals*, 2011

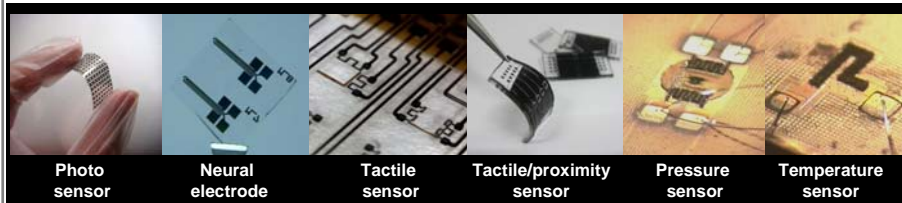


CNTs-MEMS Platform



Flexible CNTs-parylene sensor Flexible CNTs-PDMS sensor CNTs-parylene on Si structure

CNTs Parylene PDMS Metal Poly-Si SiO₂ Si Fe

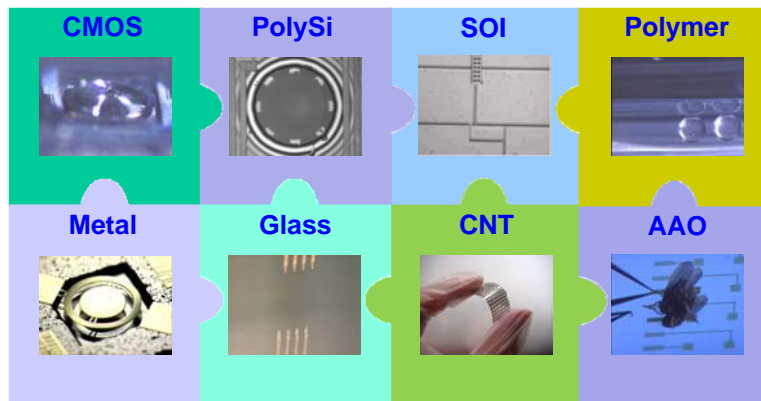


Fang, and Chu, *Adv. Materials*, 2006 Lin, and Fang, *IEEE MEMS*, Hong Kong, 2010
 Chu, and Fang, *Transducers*, Lyon, 2007 Wang, and Fang, *IEEE MEMS*, Cancun, 2011
 Lin, and Fang, *Biosens. Bioelec.*, 2009 Hu, and Fang, *Transducers*, Beijing, 2011
 Lin, and Fang, *Nanotechnology*, 2009 Hu, and Fang, *J. Micromech. Microeng.*, 2011



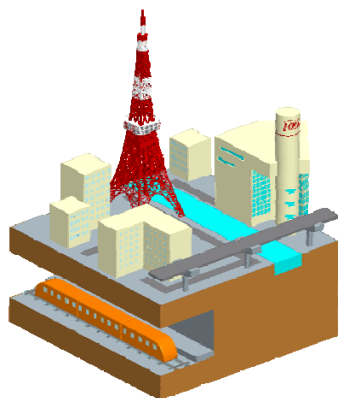


Platforms as Building Blocks

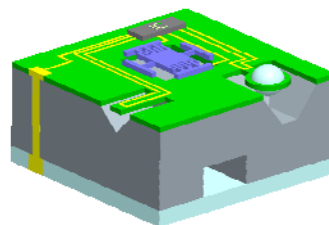


3D Architecture on Chip

- MEMS technology enables “3D” structures on chip



m ~ km



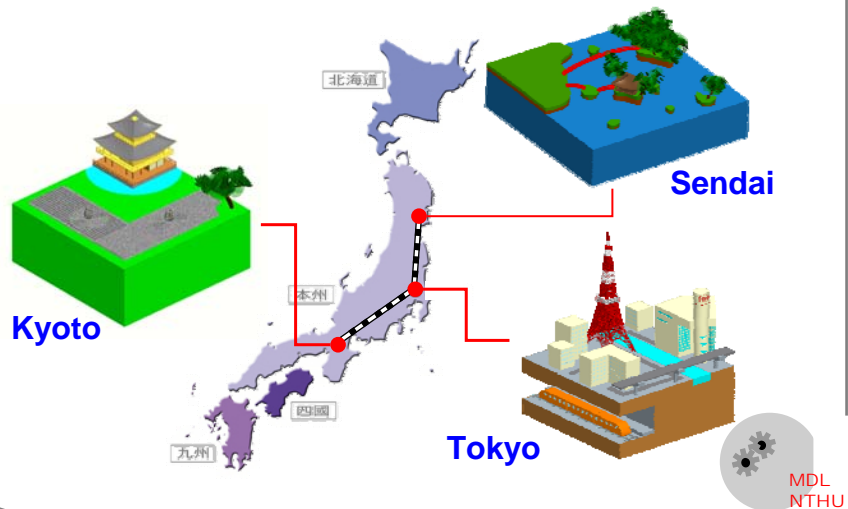
μm ~ mm





Fabrication Platform as Building Blocks

- Towards the Era of “More than Moore”: SoC/SiP/3D-IC



A Small World on Chip

- “*It’s a small world,*” ... and...
build up your own “*Magic Kingdom*” on chip



Source: www.youtube.com





Acknowledgements

- **National Science Council (NSC), Taiwan**
- **TSMC, APM, tMt, PixArt, Sitronix, Delta, ASE Domintech, Sensirion**
- **National Labs, Taiwan – CIC, NDL**
- **Fabrication Common Labs – NTHU, NCTU, NTU**
- **My graduate students**



Thank you for your attention

